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HP-41CX PROGRAMS FOR HgCdTe DETECTORS AND IR SYSTEMS

by
DAVID R. KAPLAN

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19 ABSTRACT (Continue on reverse if necessary and identify by block number) Programs have been written for the HP-41CX pocket computer which aid in the analysis of HgCdTe detectors, focal planes, and infrared systems. They have been written to run in a basic HP-41CV or HP-41CX with no card reader or additional ROMs required. An HP-41C with less than maximum RAM will be unable to hold all the programs in memory at the same time, but a subset can be loaded by hand from the enclosed listings. The purpose of this report is to describe the programs and to provide the user with information needed to use them.			
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CONTENTS

I INTRODUCTION	1
II PROGRAM DOCUMENTATION	5
1. FLAG	5
2. NEdT, DET RNG	6
3. D*, QBB	9
4. BB	12
5. SV	16
6. GR-DIFF	18
7. HCT, X, EG	21
8. NI-RØA	23
9. CONSTNT	26
10. INJEFF	28
III FINAL COMMENTS	31

**HP-41CX PROGRAMS
FOR
HgCdTe DETECTORS AND IR SYSTEMS**

I. INTRODUCTION

Programs have been written for the HP-41CX which aid in the analysis of HgCdTe detectors, focal planes, and infrared systems. They have been installed as a "bundle" in an HP-41CX and a "WALL" (write-all) operation has been performed, saving the group of programs and machine status to magnetic cards. They have been written to run in a basic HP-41CV or HP-41CX with no card reader or additional ROMs required. An HP-41C with less than maximum RAM will be unable to read this WALL configuration and will be unable to hold all the programs in memory at the same time, but a subset can be loaded by hand from the enclosed listings.

The purpose of this report is to describe the status of the HP-41CX after the WALL cards have been read, and to provide the user with information needed to use the programs.

It is assumed that the user has some familiarity with the operation and programming of the HP-41 family of pocket calculators. However, the description will begin with a brief review of the more pertinent characteristics and procedures.

The HP-41CX can have many different unique programs in memory at the same time. Jumps to perform a subroutine or to alter program flow are referred to labels (LBLs) which identify the target location. There are a limited number of short (quick) labels available, and when writing a program, it's important to keep track of label usage. The HP-41CX provides the capability, when desired, of separating programs with an END statement. The short labels cannot be reached by GTO (go to, jump) or XEQ (execute, gosub) commands beyond an END statement. This means that such labels are local labels and don't conflict with identical labels in other programs separated by an END statement. There are, however, global labels available which permit the user to go directly to a program from anywhere in RAM. These also permit one program to GTO or XEQ another program, even though they are separated by an END statement. Performing a CATALOG 1 causes the HP-41CX to list the global labels. The listing may be paused with the R/S key, and you may step forward or backward through the listing with the SST and BST keys. You may put yourself in a desired program by listing CATALOG 1, pausing with the desired program in the display, and pressing the ← key.

The global labels of the programs included in this WALL configuration are listed on the next page. Global labels need not necessarily be separated by END statements, and some of the labels in this group of programs, in fact, are not. Indented programs are included in the same local area with program above.

LABEL	DESCRIPTION
FLAG	Puts calculator flags back to a default status.
NEdt	Noise equivalent delta temperature of an IR system, and photons collected in an integration time.
DET RNG	Estimates detection range of a target.
D*	D-Star (PV, Johnson, and BLIP), RoA BLIP, D*lambda to D*BB conversion factor.
QBB	Blackbody photon flux.
BB	General purpose blackbody calculations.
SV	General purpose root finder used by other programs.
GR-DIFF	RoA, temperature, cutoff interpolator/extrapolator.
HCT	X of Hg(x)Cd(1-x)Te from cutoff and temperature.
EG	Bandgap from x and temperature.
NI	Intrinsic carrier concentration from material parameters.
ROA	RoA product from material parameters.
CONSTNT	Useful physical constants.
INJEFF	Direct Injection injection efficiency.

The following USER key definitions are also included. (In USER mode, the following keys perform the indicated operation.)

PRESSING	WILL RESULT IN
TAN	PACK
SHIFT TAN	CLRG (clear all data registers)
SHIFT R/S	Run the FLAG program

Twenty-six registers have been reserved for data storage (registers 00 through 25.) Thirty-five registers of the 319 available in an empty machine are unused and available for either additional programming or additional data storage. Each register has room for approximately five program steps. Should more room be needed for a different, lengthy program, and if you are using an HP-41CX or an HP-41C(V) with an extended memory module, you may SAVEP any program in RAM to EXTENDED MEMORY (which is similar to a RAM-DISK) and then clear the program from RAM. This may be repeated as necessary with other programs until EXTENDED MEMORY is full. Programs in EXTENDED MEMORY cannot be run, but you may GETP them back into RAM, if there is enough RAM available.

Of the 26 data registers available, only the first 15 STO (store) and RCL (recall) statements are quick access (one-byte statements instead of two-byte statements.) You can ignore this fact, but it is the reason that the first 15 registers are used most often. Since there are more than 15 different physical parameters involved in the above programs and some data registers are needed for bookkeeping or temporary scratch storage, there is not a firm relationship from global program to global program between any physical parameter and any data register. You can rest assured that the right data are in the right place at the right time when running a given program. BUT don't assume that data entered while running one program will be correctly placed, should you go to another global program which requires the same data. It is advisable to perform a CLRG (SHIFT-TAN in USER mode) and reenter all necessary data when moving to a new program.

There is a similar caution concerning the HP-41CX flags. There are 56 flags which are used by the HP-41CX, 30 of which are user alterable. The status of the first five are indicated on the LCD display. Since the calculator is slow (as computers go), some calculations are done once, the data are stored, and a flag is set to let the program know that the calculation need not be done again, unless certain parameters are altered. If these parameters are altered, the flag is automatically cleared so that a new calculation will be performed when required. Flags are used to control program flow for other reasons as well. To keep the user informed, only the first five flags (which are visible in the display) are used in this fashion. Different global programs may use the same flag to mean different things, so it is advisable when moving to a new global program (or just starting a program) to check to see that the five displayed flags (0 through 4) are clear. If you can't see them, they're clear. Running the FLAG program (SHIFT-R/S in USER mode) will insure that all flags are clear. This will leave you in the FLAG program, and then you will have to go to the program you wish to run.

Running a program generally proceeds as follows. With the exception of FLAG which may be run at any time by pressing SHIFT R/S, the user must, first, position himself within the program of interest. This may be done, as described above, by using CATALOG 1 and pressing R/S to stop the catalog scan with the desired program name in the display, or by going directly to the program of interest with the GTO command. For example, to run the blackbody program (BB), press keys as follows: SHIFT GTO ALPHA BB ALPHA.

Make sure that flags 0 through 4 are clear. It may be wise to do a CLRG to increase the likelihood that, should you fail to provide all the necessary data to the program, an error will occur or invalid results will be clearly invalid.

The programs generally require data to be input before any results may be computed. The top row of keys (A, B, C, D, E) and their SHIFTEd counterparts (a, b, c, d, e) are used to communicate with a program. This is because, *WHEN IN USER MODE*, pressing one of these keys will begin program execution at the label (LBL) which matches the key. These labels are local. If no such label exists in the current program area, then the function identified on the keyboard is executed instead. For example, suppose the current program area contains the instruction sequence:

```
.  
.   
.   
LBL d  
5  
*  
1  
+  
RTN  
.   
.   
.
```

With USER mode active, pressing SHIFT D will cause the program to be running at LBL d, where it will multiply the contents of the X register (the display) by 5, then add 1 and, finally, stop showing the answer again in the X register.

The programs are written so that pressing certain keys will cause data which have been entered into the X (or X and Y) (or X, Y, and Z) register to be stored away for later use. Pressing certain keys (perhaps after some additional data entry) will cause desired calculations to be performed and the results displayed. Which keys do what varies from program to program, and the functions are not indicated on the keyboard. You must, therefore, either remember the key definitions or refer to a document such as this report. It is common, when an individual, dedicated program is stored to a magnetic card, to write the definitions for each key on that magnetic card. The card is conceptually divided into five parts horizontally representing the five keys in the top row, and two parts vertically representing the unshifted and shifted labels. The upper half represents the shifted keys. Although this has not been done with the WALL cards, the same convention will be followed by including in each program description a drawing based on this layout which defines the operation of each key.

It is somewhat inconvenient to use a single key to enter multiple data, but it is necessary, since there is often more data required for a calculation than there are keys. Referring to one of these drawings, ENTER means press the enter key on the keyboard after keying in the requested data. This pushes the data just entered up into the Y register and permits the user to enter additional data in the X register. Another ENTER pushes the contents of Y into Z, X into Y, so additional data may be placed in X. After keying in all the requested data for a key, press that key so that the program will store it. Continue from key to key, entering in all data required to compute the parameter desired. Note that some programs calculate more than one parameter and that some parameters may not require that all the data indicated on the drawing be input. Which parameters require which data comes from experience or referral to this report.

Once all the necessary data have been keyed and stored, pressing the FIND key for the desired parameter will initiate the calculation to produce the answer for that parameter. Obviously, pressing FIND before all the necessary support data have been entered will, very likely, produce invalid results. It may even produce an operational error; e.g., divide by zero, causing the calculation to terminate. Under

most circumstances no harm is done when this occurs. However, *NOTE* that some programs call other programs. If the error occurs in the called program, you will be left in that program, not in the program from which you started. It is advisable, should such an improper termination occur, to re-position yourself via CATALOG 1 or GTO to the program of interest. It is probably, also, wise to clear any set flags.

If incorrect data have been keyed and stored, it may be corrected by performing the correct data entry sequence for the key dedicated to that data. This means that you will have to reenter all the data associated with that key. This is also true if you wish to change any data, either before or after FINDing a result. To recalculate a result with different initial conditions, you need only reenter the data associated with the key whose data you wish to alter. Then, press the appropriate FIND key for the result desired.

What follows is user documentation and description for each of the programs.

II. PROGRAM DOCUMENTATION

1. FLAG. This is a very short program designed specifically to restore all 55 flags of the HP-41CX to default status. It clears flags 0 through 25, sets the display to FIX 2 format, sets DEG mode, calls for a period as the decimal point, and calls for commas between digit groupings of three. It alters no data registers. This program may be quickly run by pressing SHIFT R/S in the USER mode if FLAG has been assigned to this key.

The FLAG program on the WALL cards contains undocumented program steps and should not be altered or single-stepped in RUN mode.

Also, included is a listing for FLAG which simulates the short version and which contains no undocumented operations. This version is significantly slower than the short version, but it may be keyed by hand and needs no precautions.

PROGRAM LISTINGS FOR FLAG

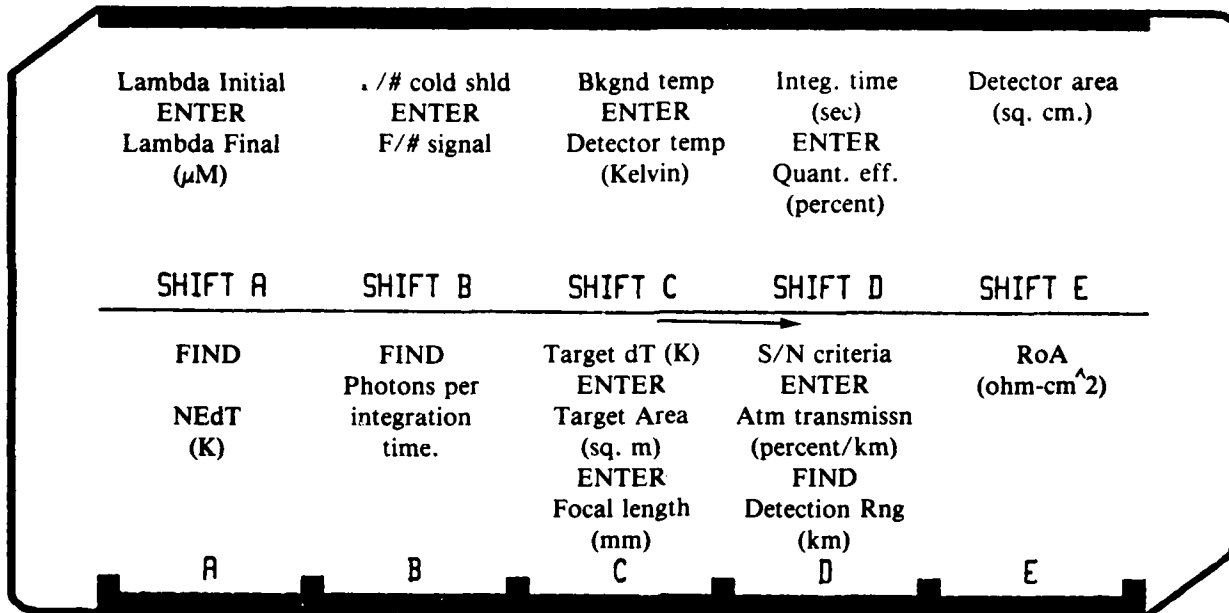
Two listings are given. The first is very fast and short but contains undocumented code which can only be created by procedures unavailable to most users. It is included on the WALL cards. The second is longer and significantly slower but may be easily keyed by hand.

01/10/1986

```
01*LBL "FLAG"  
02 "<X*"  
03 ASTO d  
04 CF 03  
05 .END.
```

```
01*LBL "FLAG"  
02 .025  
03*LBL 00  
04 CF IND X  
05 ISG X  
06 GTO 00  
07 SF 26  
08 SF 27  
09 SF 28  
10 SF 29  
11 FIX 2  
12 DEG  
13 RTH  
14 END
```

2. NEdT, DET RNG.



Below is a table showing the data required, registers used, sample test data, and results.

	REQ'D FOR NEdT	REQ'D FOR PHOTONS	REQ'D FOR DET RNG	REGISTER USED	TEST DATA
LAMBDA INITIAL	X	X	X	1	3
LAMBDA FINAL	X	X	X	10	5
F/# COLD SHIELD	X		X	17*	1
F/# SIGNAL	X	X	X	4	1.4
BACKGROUND TEMPERATURE	X	X	X	3	300
DETECTOR TEMPERATURE	X		X	14	200
INTEGRATION TIME	X	X	X	5	4E-5
QUANTUM EFFICIENCY	X	X	X	18	60
DETECTOR AREA	X	X	X	2	1E-5
RoA	X		X	15	50
TARGET DELTA TEMP			X	16	3
TARGET AREA			X	11	3
SYSTEM FOCAL LENGTH			X	12	100
S/N CRITERIA			X	13**	10
ATM. TRANSMISSION (PERCENT/KM)			X	20***	70.71

RESULTING NEdT = 0.15511 K
 RESULTING SIGNAL PHOTONS = 4.02 E5
 RESULTING DETECTION RANGE = 3.885 km

Other registers used:
 0,6,7,8,9

- * This register actually contains the ratio of the f/numbers squared.
- ** This register used for scratch as well, so S/N not saved.
- *** SQR (transmission percent/100) actually stored.

This program finds (1) Noise equivalent delta temperature (NEdT), (2) number of photons collected by a detector (or an equivalent detector, for TDI) through the system in an integration time, and (3) detection range for a target.

The NEdT for an IR system is calculated from certain system and detector parameters. It is a relatively abbreviated calculation, so the results are only approximate. Assumptions made include that the noise comes only from the detector or the background, that the noise bandwidth is the reciprocal of the integration time, that the quantum efficiency is constant with respect to wavelength, and that the detector noise is due to shot noise at zero bias.

The calculation performed is:

$$NEdT = \frac{SQR(2*PC + (4kTt/Ro/e^2))}{SC}$$

where Q.E. is the detector quantum efficiency;

t = detector integration time;

T = detector temperature;

Ro = detector zero bias dynamic resistance;

A = detector active area; and

PC is the charge absorbed by the detector/t due to photons.

or,

$$PC = \frac{Q A (Q.E.) t}{(2 * (\text{cold shield } F/\#))^2}$$

where Q = photon flux rate from cuton to cutoff/cm²/s, and

SC is the signal charge absorbed by the detector/t per degree change in scene temperature.

or,

$$SC = \frac{dQ}{dT} \frac{A (Q.E.) t}{(2 * (\text{signal } F/\#))^2}$$

where $\frac{dQ}{dT}$ = change in signal flux per change in scene temp.

The photons per integration time, found by pressing key B, is the number of SIGNAL photons collected through the optics of the indicated system (using the signal F/#) which produces signal carriers. For TDI systems the integration time entered should be the integration time per detector times the number of detectors in TDI, so that the number of carriers accumulated is the number for the TDI column. To find the number of background carriers collected, set the signal F/# equal to the background F/#.

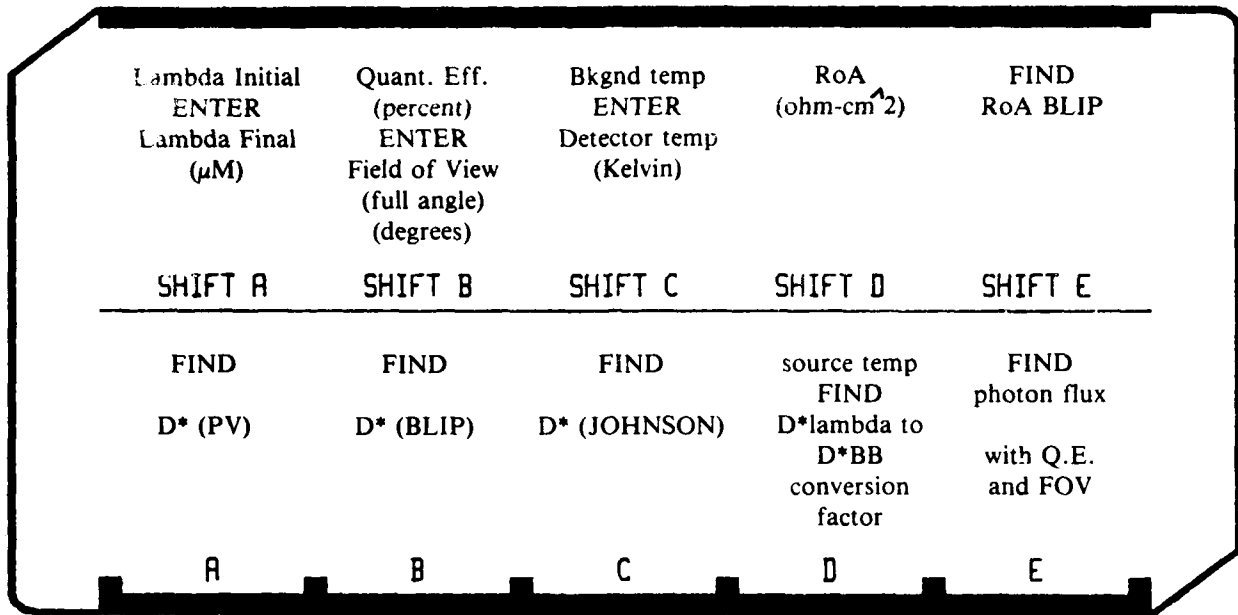
The detection range is calculated by finding the range at which the image of the target is sufficiently smaller than the detector, so that the S/N is as desired. The signal is attenuated, based upon the entered atmospheric transmission per kilometer. The SV (solve) program is called to perform the iteration to a solution.

$$S/N = (\text{transmission})^{\wedge}(\text{range}) \times \frac{(\text{target delta } T)}{NEdT} \times \frac{(\text{target area})}{A} \times \frac{f^2}{\text{Range}^2}$$

PROGRAM LISTING FOR NEdT, DET RNG

01/10/1986	51 RCL 13	104 X↑2	157 X↑2
	52 *	105 STO 17	158 /
	53 RCL 07	106 RTN	159 +
01*LBL "DET RNG"	54 -	107*LBL c	160 RCL 08
02*LBL C	55 RTN	108 STO 14	161 9
03 STO 12	56*LBL "NEdT"	109 X<>Y	162 *
04 RDN	57*LBL A	110 STO 03	163 6
05 STO 11	58 .5	111 RTN	164 +
06 RDN	59 ST+ 03	112*LBL d	165 RCL 08
07 STO 16	60 SF 00	113 STO 18	166 *
08 RTN	61 XEQ 08	114 X<>Y	167 2
09*LBL D	62 STO 06	115 STO 05	168 +
10 100	63 1	116 RTN	169 27
11 /	64 ST- 03	117*LBL e	170 /
12 SQRT	65 XEQ 08	118 STO 02	171 RCL 07
13 STO 20	66 CF 00	119 RTN	172 X↑2
14 X<>Y	67 .5	120*LBL E	173 /
15 STO 13	68 ST+ 03	121 STO 15	174 RCL 07
16 XEQ "NEdT"	69 RDN	122 RTN	175 /
17 RCL 13	70 RCL 06	123*LBL B	176 +
18 *	71 X<>Y	124 CF 00	177 RCL 03
19 RCL 16	72 ST- 06	125*LBL 08	178 X↑2
20 X<>Y	73 +	126 SF 01	179 *
21 "NO DETECT"	74 RCL 17	127 RCL 01	180 RCL 03
22 X>Y?	75 /	128 XEQ 01	181 *
23 PROMPT	76 215 E13	129 STO 00	182 1581 E5
24 /	77 RCL 14	130 RCL 10	183 *
25 RCL 12	78 *	131*LBL 01	184 RCL 18
26 X↑2	79 RCL 15	132 14388	185 *
27 RCL 11	80 /	133 X<>Y	186 RCL 04
28 *	81 RCL 02	134 /	187 X↑2
29 RCL 02	82 *	135 RCL 03	188 /
30 /	83 RCL 05	136 /	189 RCL 02
31 *	84 *	137 STO 08	190 *
32 SQRT	85 +	138 2	191 RCL 05
33 1 E4	86 SQRT	139 +	192 *
34 /	87 RCL 06	140 RCL 08	193 FS?C 01
35 STO 13	88 /	141 *	194 RTN
36 SF 10	89 FIX 5	142 2	195 RCL 00
37 "R"	90 "NEdT="	143 +	196 -
38 ASTO 06	91 ARCL X	144 RCL 08	197 FS? 00
39 0	92 AVIEW	145 E↑X	198 RTN
40 X<>Y	93 RTN	146 STO 07	199 SCI 2
41 FIX 3	94*LBL a	147 /	200 CLA
42 XEQ "SV"	95 STO 10	148 RCL 08	201 ARCL X
43 CLA	96 X<>Y	149 X↑2	202 "F PHOT"
44 ARCL X	97 STO 01	150 RCL 03	203 AVIEW
45 "FKM"	98 RTN	151 +	204 RTN
46 PROMPT	99*LBL b	152 .5	205 END
47*LBL "R"	100 X<>Y?	153 +	
48 RCL 20	101 GTO 99	154 2	
49 X<>Y	102 STO 04	155 /	
50 Y↑X	103 /	156 RCL 07	

3. D*, QBB.



Below is a table showing the data required, registers used, sample test data, and results.

	REQ'D FOR D*PV	REQ'D FOR D*BLIP	REQ'D FOR D*JHNSN	REQ'D FOR C.F.	REQ'D FOR P. FLUX	REQ'D FOR RoABL	RGSTR USED	TEST DATA
LAMBDA INITIAL	X	X		X	X	X	5	8
LAMBDA FINAL	X	X		X	X	X	10	11
QUANTUM EFFICIENCY	X	X			X	X	11	50
FIELD OF VIEW	X	X			X	X	13	120
BACKGROUND TEMP.	X	X				X	12	300
DETECTOR TEMPERATURE	X		X			X	14	80
RoA	X		X				9	0.1
SOURCE TEMPERATURE				X			12*	500

RESULTING D*PV = 1.93 E10
 RESULTING D*BLIP = 4.82 E10
 RESULTING D*JOHNSON = 2.11 E10
 RESULTING CONVERSION FACTOR = 5.60
 RESULTING PHOTON FLUX = 1.65 E17/CM²/SEC
 RESULTING RoA BLIP = 0.522

OTHER REGISTERS USED:
0,6,7,8,15

*Source temperature is placed temporarily in register 12; background temperature is restored to register 12, at the end of the calculation.

This program contains routines to find six different parameters associated with photovoltaic detector D-star.

(1) D*JOHNSON is the detectivity based on the assumption that the detector shot noise at zero bias is the only noise source. It is computed from:

$$D^*JOHNSON = \frac{e(Q.E.) \text{ (cutoff)} \text{ SQR}(Ro^*A/(4kT))}{hc}$$

(2) D*BLIP is the detectivity based on the assumption that the background noise is the only noise source. It is computed from:

$$D^*BLIP = \frac{\text{ (cutoff)} \text{ SQR}((Q.E.)/(\text{photon flux}))}{\text{SQR}(2) h c \text{ SIN}(FOV/2)}$$

(3) D*PV is the detectivity which includes both detector and background noise sources and is computed from the above as:

$$D^*PV = \frac{(D^*JOHNSON) (D^*BLIP)}{\text{SQR}((D^*JOHNSON)^2 + (D^*BLIP)^2)}$$

(4) Blackbody photon flux is the photon collection rate per second per square centimeter of detector area for the given quantum efficiency and field of view. It is found by twice calling a routine which calculates the flux from lambda = 0 up to lambda. Lambda is first set to cutoff, then to cuton, and the results are subtracted. The basic routine which is called is:

$$Q = a \frac{\text{SUM}(X^2 + 2^*X/n + 2/n^2)}{n \text{ EXP}(nX)}, \quad \text{for } n = 1,2,3 \text{ and } X = \text{lambda, and}$$

$$\text{where } a = 2 \text{ PI } c (kT/(hc))^3.$$

(5) The conversion factor is the factor which converts a blackbody D* to a lambda peak D*. It is a theoretical value which, here, assumes that the quantum efficiency of the detector is constant between cuton and cutoff. For this calculation, it is assumed that the peak response is at the cutoff. It is calculated from (where sigma is the Stefan-Boltzmann constant):

$$C.F. = (\text{photon flux}) (b/a), \text{ where } a \text{ is as above, and}$$

$$b = \frac{2 \text{ PI } k^3}{c (\text{sigma}) (\text{source temperature}) h^2 (\text{lambda cutoff})}$$

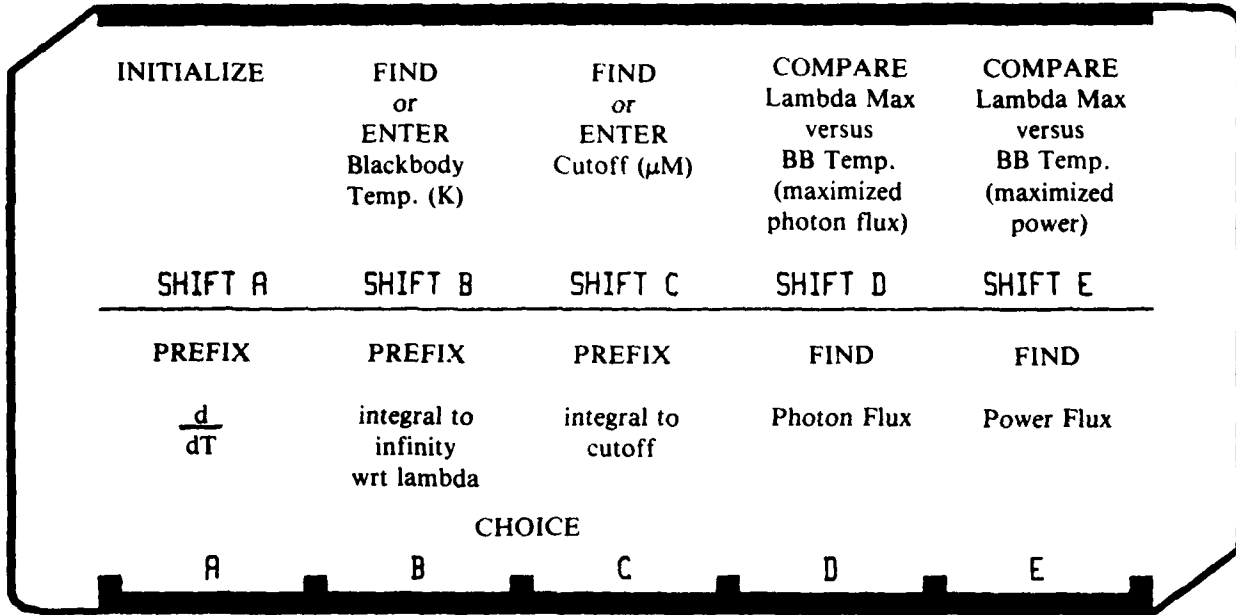
(6) RoA BLIP is the value of the RoA for which D*JOHNSON and D*BLIP equal one another. It is, therefore, the RoA for which the D*PV is .7071 of D*BLIP. Requesting this calculation presents the answer in the display and, also, stores this value in register 9. This means that further calculations for D* will be based on this RoA.

PROGRAM LISTING FOR D*, QBB

01/10/1986

01+LBL e	49 XEQ 08	101+LBL 00
02 1	50 RCL 06	102 2
03 STO 09	51 -	103 RCL 07
04 XEQ B	52 FS? 02	104 /
05 XEQ C	53 RTN	105 RCL 08
06 /	54 RCL 13	106 +
07 X+2	55 2	107 RCL 08
08+LBL d	56 /	108 *
09 STO 09	57 SIN	109 2
10 RTN	58 X+2	110 RCL 07
11+LBL a	59 *	111 X+2
12 CF 00	60 RCL 11	112 /
13 STO 10	61 %	113 +
14 X<>Y	62 STO 15	114 RCL 07
15 STO 05	63 SF 00	115 /
16 RTN	64 RTN	116 RCL 08
17+LBL b	65+LBL B	117 RCL 07
18 CF 00	66 XEQ E	118 *
19 STO 13	67 SQRT	119 E+X
20 X<>Y	68 RCL 11	120 /
21 STO 11	69 X<>Y	121 +
22 RTN	70 /	122 DSE 07
23+LBL c	71 RCL 10	123 GTO 00
24 CF 00	72 *	124 FS? 02
25 STO 14	73 356 E14	125 RTN
26 X<>Y	74 *	126 RCL 12
27 STO 12	75 RTN	127 X+2
28 RTN	76+LBL C	128 RCL 12
29+LBL "B*"	77 SCI 2	129 *
30+LBL A	78 RCL 09	130 6324 E7
31 XEQ B	79 RCL 14	131 *
32 XEQ C	80 /	132 *
33 R-P	81 SQRT	133 RTN
34 STO 08	82 RCL 10	134+LBL D
35 P-R	83 *	135 X<> 12
36 *	84 RCL 11	136 STO 00
37 RCL 08	85 *	137 CF 00
38 /	86 10854 E5	138 SF 02
39 RTN	87 *	139 XEQ E
40+LBL E	88 RTN	140 CF 02
41 SCI 2	89+LBL "QBB"	141 2216
42 RCL 15	90+LBL 08	142 *
43 FS? 00	91 3	143 RCL 10
44 RTN	92 STO 07	144 /
45 RCL 05	93 CLX	145 RCL 12
46 XEQ 08	94 14388	146 /
47 STO 06	95 X<>Y	147 RCL 08
48 RCL 10	96 /	148 STO 12
	97 RCL 12	149 RDN
	98 /	150 1/X
	99 STO 08	151 END
	100 CLX	

4. BB.



Below is a table showing sample test data and results.

LAMBDA FINAL = 5 μM (not required for integral to infinity)
 BLACKBODY TEMP. = 300K REGISTERS USED: 0 THRU 15

RESULTS

PREFIXES PRESSED	Q (photons)	W (watts)
NONE	2.058 E16 /cm ² /s/ μM	8.175 E-4 /cm ² / μM
INTEGRAL TO INFINITY (ITI)	4.105 E18 /cm ² /s	4.592 E-2 /cm ²
INTEGRAL TO CUTOFF (ITC)	1.320 E16 /cm ² /s	5.901 E-4 /cm ²
DERIVATIVE WRT TEMP (DWT)	6.580 E14 /cm ² /s/ μM /K	2.614 E-5 /cm ² / μM /K
DWT, ITI	4.105 E16 /cm ² /s/K	6.123 E-4 /cm ² /K
DWT, ITC	4.749 E14 /cm ² /s/K	2.149 E-5 /cm ² /K

The COMPARE functions permit you to key in either wavelength or temperature and calculate the other (temperature or wavelength) for maximum flux. For example, keying in 300 and pressing SHIFT D will produce the value 12.23. This means that for a 300 K blackbody, the wavelength of peak photon flux

density is 12.23 μM . Or conversely, a blackbody whose peak photon flux density is at 300 μM wavelength has a temperature of 12.23 K. The operation for SHIFT E is the same, except the criterion is the wavelength for peak power density. Keying 300 and SHIFT E produces the value 9.659. NOTE: The data entered prior to a COMPARE operation does not alter any values that have been stored for wavelength or temperature via SHIFT B or SHIFT C.

This program uses the keys a little differently. First, before doing anything else, you must initialize the program by pressing SHIFT A. This configures the HP41 data registers and flags for the rest of the program. It also is used to clear partial entries, as described below.

Second, at most only two initial conditions are required, wavelength and temperature, and the keys which are used to store these conditions may also be used to recall (or verify) them. The HP41 has a flag which it uses to keep track of whether a numeric key (0 through 9) has been pressed. This flag is not visible in the display. As soon as any numeric key is pressed, this flag gets set. The program uses this fact to determine if the user is storing data or requesting an answer. If the flag is set, the user is assumed to be storing data, and the value in the display is stored as the new value of the variable designated by the key pressed. If the flag is clear, the present value of the requested variable is displayed. The program clears this flag automatically after every operation, so the presence (or absence) of new numeric key presses may be sensed. NOTE: If this flag is set and any of the unshifted keys are pressed, the program updates the wavelength with the current value in the X register (the display), in addition to performing the desired operation. If you have done some simple keyboard calculations (thereby setting the flag), and you now wish to perform a program operation without altering the value for wavelength, press the INITIALIZE key, first. This clears the flag without altering the current values for wavelength and temperature.

Third, keys A, B, and C are not used for data entry, but may be used for configuring the program for the type of calculation to be performed. For example, pressing D or E without first pressing A, B, or C will result in the calculation of the photon flux density in photons/cm²/s/ μM or power density in W/cm²/ μM , respectively. See the table showing sample test data and results. Pressing A first, for example, then pressing D or E will result, instead, in the calculation of the change in flux (either photons or power) per degree change in blackbody temperature. You may press pairs of prefix keys prior to calling for a calculation (e.g., A, C, E to find the change in power up to the cutoff per degree Kelvin). The prefix keys may be pressed in any sequence as long as you end up pressing D or E. NOTE: It doesn't make sense to use both B and C. The last one pressed takes precedence. If you have pressed any prefix keys and change your mind (or have made an error), pressing the INITIALIZE key will cancel and give you a fresh start. Stored values for wavelength and temperature are unaffected.

At the end of a calculation, the program displays in sequence (1) the key sequence which has been performed, (2) the temperature that was used, (3) the wavelength that was used, and (4) finally, the answer. The key sequence is displayed numerically proceeding from left to right, where the numbers represent the respective unshifted keys. Key A is 1, key B is 2; etc. For example, pressing C, A, D will display a key sequence of 314.000, where the number of trailing zeros depends upon the current display setting.

The following equations and procedures are used in BB (L = wavelength).

$$\text{EQN1} = c_1(T/c_2)^{-p} \sum_{n=1}^{\text{inf}} \{ (l+p-1)! / n^2 \text{EXP}(-nc_2/LT) \sum_{m=0}^{l+p-1} \{ (nc_2/LT)^m / m! \} \}.$$

$$\text{EQN2} = c_1 / [L^{l+p+1} (\text{EXP} \{ c_2/LT \} - 1)].$$

$$\text{EQN3} = c_1 \text{EXP} (c_2/LT) / [T^2 (\text{EXP} \{ c_2/LT \} - 1)].$$

$$\text{EQN4} = zc_1 (T/c_2)^{-p} (l+p-1)!$$

Default conditions are: $p=0$, $c_1 = hc^2/(2\pi) = 37415$, $c_2 = hc/k = 14388$, $z_{c1} = 40495$ and use EQN2.

If prefix key A is used, then $p=1$; if using EQN2, then multiply by EQN3, and divide answer by c_2 .

If prefix key B is used, then use EQN4, instead.

If prefix key C is used, then use EQN1, instead.

If calculating power, then $l = 4$.

If calculating photon flux, then $l = 3$; use $c_1 = 1/k = 18837E19$, instead; if using EQN4, then use $z_{c1} = 22642E19$, instead.

Using these equations and logical tests in this fashion permits calculation of many different parameters in a small program space.

PROGRAM LISTING FOR BB

01/10/1986

01+LBL "08"
 02+LBL a
 03 37415
 04 STO 04
 05 14388
 06 STO 10
 07 18837 E19
 08 STO 03
 09 CLX
 10+LBL 01
 11 0
 12 STO 15
 13 STO 14
 14 STO 09
 15 X<Y
 16 CF 00
 17 SF 01
 18 CF 22
 19 SCI 3
 20 RTN
 21+LBL b
 22 FS?C 22
 23 STO 11
 24 RCL 11
 25 RTN
 26+LBL A
 27 CF 01
 28 XEQ 07
 29 1
 30 GTO 05
 31+LBL B
 32 SF 02
 33+LBL C
 34 XEQ 07
 35 3
 36 FS?C 02
 37 2
 38 STO 15
 39+LBL 05
 40 RCL 14
 41 10
 42 *
 43 +
 44 STO 14
 45 FIX 0
 46 RTN
 47+LBL 07
 48+LBL c
 49 SCI 3
 50 FS?C 22

51 STO 12
 52 RCL 12
 53 RTN
 54+LBL D
 55 SF 00
 56+LBL E
 57 XEQ 07
 58 RCL 10
 59 RCL 11
 60 /
 61 STO 13
 62 RCL 12
 63 X#0?
 64 /
 65 STO 00
 66 4
 67 FS? 00
 68 3
 69 STO 05
 70 STO 01
 71 STO 02
 72 1
 73 STO 00
 74 FS? 01
 75 GTO 14
 76 ST+ 01
 77 ST- 02
 78+LBL 14
 79 +
 80 XEQ 05
 81 RCL 04
 82 FS? 00
 83 RCL 03
 84 STO 06
 85 GTO IND 15
 86+LBL 00
 87 RCL 12
 88 RCL 01
 89 1
 90 +
 91 Y↑X
 92 /
 93 RCL 00
 94 E↑X
 95 STO 09
 96 1
 97 -
 98 /
 99 FS? 01
 100 GTO 01
 - 101 LASTX
 102 /
 103 RCL 09

104 *
 105 RCL 13
 106 X↑2
 107 *
 108 RCL 10
 109 /
 110 GTO 01
 111+LBL 02
 112 1.202
 113 ENTER↑
 114 1.0823
 115 FS? 00
 116 X<Y
 117 STO 09
 118 GTO 02
 119+LBL 03
 120 RCL 01
 121 STO 15
 122 0
 123 RCL 08
 124 RCL 00
 125 *
 126 STO 07
 127+LBL 04
 128 RCL 15
 129 1
 130 -
 131 Y↑X
 132 LASTX
 133 FACT
 134 /
 135 +
 136 RCL 07
 137 DSE 15
 138 GTO 04
 139 E↑X
 140 /
 141 RCL 00
 142 RCL 05
 143 Y↑X
 144 /
 145 ST+ 09
 146 RCL 09
 147 /
 148 FS? 00
 149 R-D
 150 FIX 3
 151 RND
 152 ISG IND 15
 153 CLA
 154 X#0?
 155 GTO 03
 156+LBL 02

157 RCL 06
 158 RCL 13
 159 RCL 02
 160 Y↑X
 161 /
 162 RCL 01
 163 1
 164 -
 165 FACT
 166 *
 167 RCL 09
 168 *
 169 FS? 01
 170 GTO 01
 171 RCL 10
 172 /
 173 GTO 01
 174+LBL e
 175 .7896
 176 /
 177+LBL d
 178 3670
 179 /
 180 1/X
 181 SCI 3
 182 CF 22
 183 END

5. SV. This program is a short, root-solving program which uses the secant method to iterate to a real solution of arbitrary, user-defined functions of the form: $F(x) = 0$. It is included here, since it is used as a subroutine by other programs in this write-all configuration. It may, also, be used for other applications as well.

The SV routine expects to find the name of the global label of the function to be solved in register 6 and an initial guess for X in register X (the display.) Do NOT use an initial guess of zero for X. Registers 6, 7, 8, and 9 are used by SV. XEQing SV will then result in an iterative, hopefully convergent, search for a value of X which makes the function identified in register 6 equal to zero. The successive values of X are displayed, so you can watch the search converge (or diverge). Termination of the search automatically occurs, when two successive values of X are equal within the resolution of the current display setting. This means that the accuracy of the answer may be determined by pre-selecting a display setting. Upon termination, the solution for X is in the X register (display) and in register 7. NOTE: When a program is running, the PRGM annunciator is visible in the display. When the program stops, the annunciator goes out.

For example, suppose we wish to find the solution to the equation:

$$X = 10^{(-X)}.$$

This must be rewritten to take the form $F(x) = 0$, so:

$$0 = X - 10^{(-X)}.$$

A program which performs this function and which starts with a global label must be written. Any two-letter, alphabetic label is global, so let's use the label "FN". (Assume X starts in the X register, and the answer is to be left in the X register.) The program would then look like:

LBL FN	The global label so SV can call it.
ENTER	Starting value in X; duplicate it in Y.
$10^{\wedge}X$	Raise 10 to the X power.
1/X	Take the reciprocal (yields $10^{(-X)}$).
-	Subtract X from Y, leaving answer in X.
RTN	Return to calling routine.

Next, place the label of the function to be solved into register 6: ALPHA FN SHIFT STO 06 ALPHA.
 Set the display to 5 significant figures: SHIFT FIX 5
 Key in an initial guess: 1
 Execute the SV routine: XEQ ALPHA SV ALPHA

The routine will be observed to go through six iterations; finally, stopping at a solution for X of .39901. Executing FN with this value in the X register produces a result of 1 E-10 which is reasonably close to zero.

SV properly converges for routines in this WALL. However, for some user functions, it may have problems with bad initial guesses, or where multiple solutions exist (particularly, when some are imaginary), or when Xs near a root are invalid arguments (e.g., $SQR(X) = 0$ can't tolerate negative Xs.)

PROGRAM LISTING FOR SV

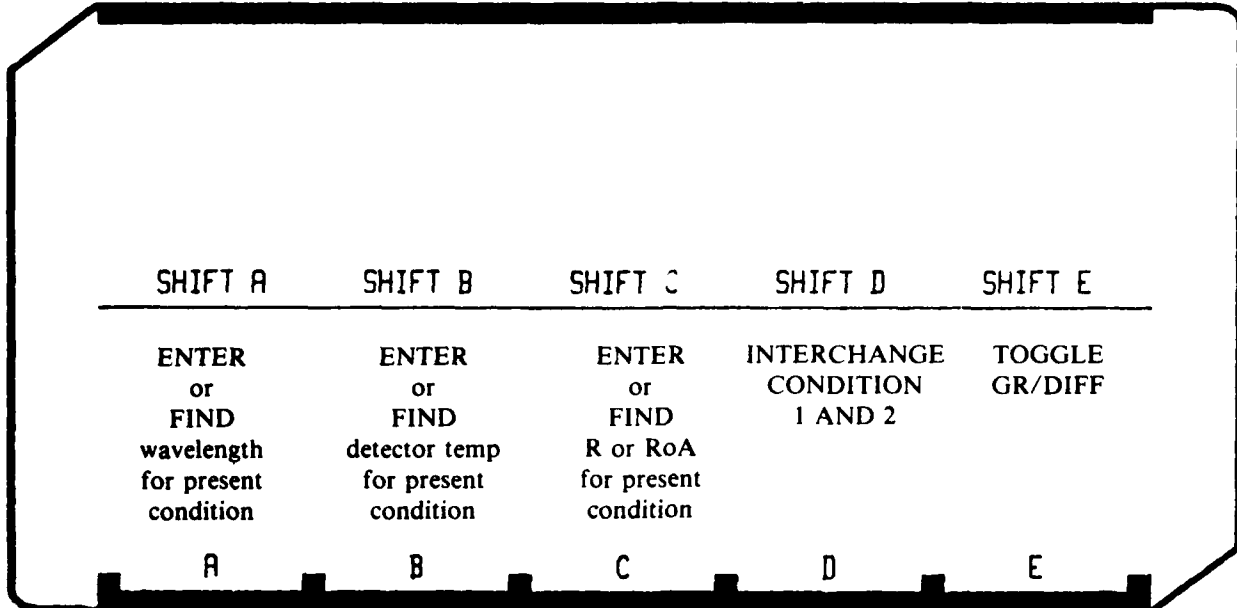
08 AUG 86

PRP "SV"

01♦LBL "SV"
02 STO 07
03 XEQ IND
06
04 STO 08
05 RCL 07
06 1
07 %
08 STO 09
09 ST- 07

10♦LBL 00
11 VIEW 07
12 RCL 07
13 XEQ IND
06
14 ENTER↑
15 ST- 08
16 X<> 08
17 /
18 ST* 09
19 RCL 09
20 ST- 07
21 RCL 07
22 +
23 RND
24 RCL 07
25 RND
26 X*Y?
27 GTO 00
28 RCL 07
29 RTN
30 .END.

6. GR-DIFF.



Below is a table showing six example pieces of data describing two different test conditions. Any five of these may be entered, and the program will solve for the sixth. The solution will assume either a diffusion limited detector or a G-R limited detector, depending on the status of the GR-DIFF toggle.

CONDITION	WAVELENGTH (μM)	TEMPERATURE (K)	R or RoA
1	9	80	10
2 (DIFF LTD.)	11.5	65	4.8
2 (G-R LTD.)	11.5	65	6.9

NOTE: If you can't remember the key definitions, press SHIFT RTN R/S.

The purpose of this program is to permit you to enter reported performance data for detectors which have the "wrong" cutoff or were tested at the "wrong" temperature and to extrapolate how the detectors would perform, if they had the "right" cutoff and/or were tested at the "right" temperature. Or, for example, you can take reported data and predict what temperature and/or wavelength of operation would be required to meet a desired R or RoA. One must assume a measure of quality of the detectors by specifying whether they are diffusion limited or G-R limited. This is done by pressing the GR/DIFF toggle. Current status is indicated prior to any result being displayed.

Only three keys (A, B, and C) are used to enter any of the six data. A is used for wavelength for both test conditions. B is used for temperature for both test conditions. C is used for R or RoA for both test conditions. Alternating between conditions is done with the D key. After any entry, the display will show the status of ALL THREE parameters for the current test condition. Read these values from left to right in the same order as keys A, B, and C. That is, wavelength, temperature, R or RoA. The parameters are separated by a ? mark until a calculation is requested which makes all six data consistent.

For example, viewing the sample data at the beginning of par 6., suppose we were presented with test condition 1 and wanted to know what RoA to expect for a diffusion limited diode under test condition 2. If you're not sure whether the GR-DIFF toggle is set to the diffusion limited case, press the toggle once and see what condition occurs. If it's GR; then, press it again. **NOTE:** Performing a CLR (SHIFT TAN) clears all registers and defaults to the diffusion limited case. Press 9, A, 80, B, 10, C, D (to

interchange which condition keys A, B, and C affect, and which condition is displayed), 11.5, A, 65, B, C (to solve for RoA for this condition). You may toggle between (and view) the two test conditions, at any time, by pressing D. You may toggle between diffusion limited and G-R limited operation, at any time, by pressing E. NOTE: If the calculation has been performed for one mode of operation (Say, G-R), and the other mode is selected, ? marks are restored to the display to indicate inconsistent data.

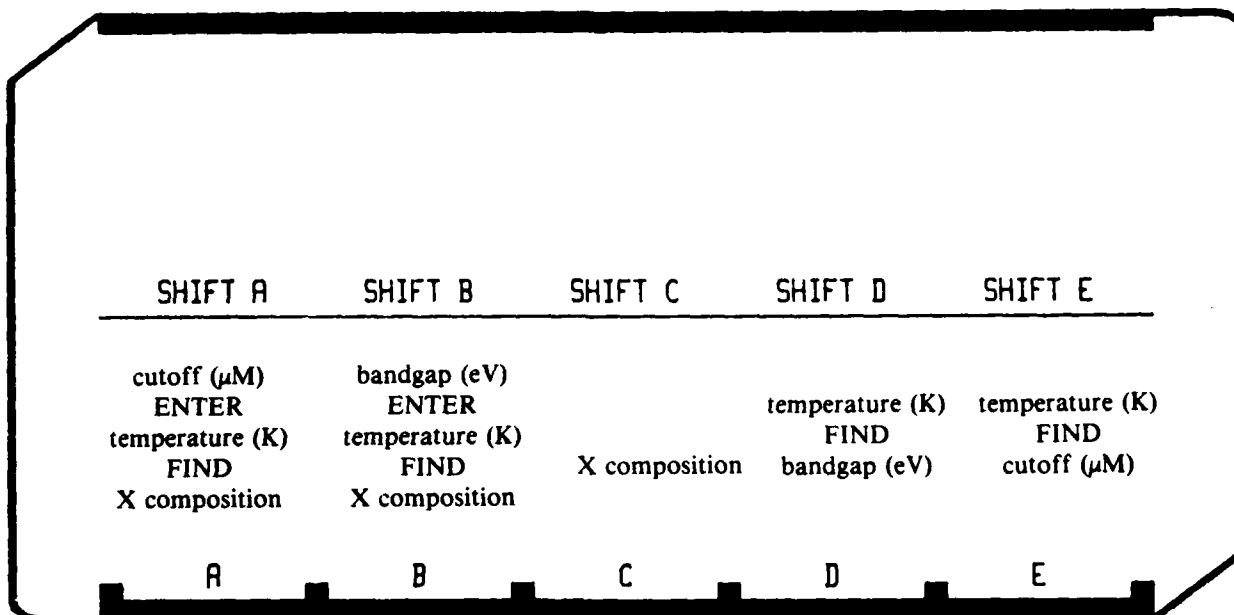
The program may also be used when one of the test conditions is diffusion limited, and the other is G-R limited. But you have to get from here to there in two steps, and you must know (or assume) the temperature at which the break from diffusion limited to G-R limited operation occurs. For example, suppose a diode with a 4.2 μM cutoff at 195 K has an Ro of 1E6 ohms. The break from diffusion limited to G-R limited operation for these diodes normally occurs near 130 K. You want to know what Ro to expect at 80 K. Strictly speaking, the cutoff will have changed when the diode is cooled to 80 K, but ignore that fact here. The procedure is as follows: CLRG (clears all registers and puts the machine into diffusion-limited regime, 4.2, A, 195, B, 1E6, C (test condition 1 now contains the 195 K performance), D, 4.2, A, 130, B, C (test condition 2 now contains the Ro at 130 K, diffusion limited, Ro = 6.5 E9), E (to toggle to G-R limited), D (test condition 1 will now represent the 80 K performance) (wavelength is still 4.2, so no need to reenter), 80, B, C (to find the G-R limited Ro at 80 K). The answer is Ro = 2.5 E13. More correct would be to use the correct predicted values for the wavelength at 130 K and 80 K, but solution for such parameters won't be covered until discussion of program HCT (par 7.).

PROGRAM LISTING FOR GR-DIFF

01/10/1986

01*LBL "GR-DIFF"	51 "?"	104 RCL 10
02 "a,T,RA,SHIFT,GD"	52 ASTO 14	105 RCL 11
03 PROMPT	53 STO 07	106 *
04*LBL D	54 FS?C 22	107 1/X
05 RCL 09	55 GTO 01	108 +
06 X<> 10	56 XEQ 04	109 1/X
07 STO 09	57 XEQ 02	110 RCL 09
08 RCL 08	58 14388	111 RCL 08
09 X<> 11	59 RCL 13	112 FS? 00
10 STO 08	60 /	113 X<>Y
11 RCL 07	61 STO 06	114 RDN
12 X<> 12	62 RCL 09	115 /
13 STO 07	63 RCL 08	116 FS? 00
14*LBL 01	64 *	117 STO 09
15 CLA	65 /	118 FC?C 00
16 FIX 2	66 RCL 06	119 STO 08
17 ARCL 09	67 RCL 10	120 " "
18 ARCL 14	68 RCL 11	121 ASTO 14
19 FIX 0	69 *	122 GTO 01
20 ARCL 08	70 /	123 END
21 ARCL 14	71 -	
22 SCI 1	72 E+X	
23 ARCL 07	73 RCL 12	
24 PROMPT	74 *	
25*LBL 04	75 STO 07	
26 1	76 " "	
27 RCL 13	77 ASTO 14	
28 X=Y?	78 GTO 01	
29 RTN	79*LBL B	
30 2	80 "?"	
31 X=Y?	81 ASTO 14	
32 RTN	82 STO 08	
33*LBL E	83 FS?C 22	
34 "?"	84 GTO 01	
35 ASTO 14	85 GTO 00	
36 RCL 13	86*LBL A	
37 1	87 "?"	
38 X=Y?	88 ASTO 14	
39 2	89 STO 09	
40 STO 13	90 FS?C 22	
41*LBL 02	91 GTO 01	
42 "DIFFUS,H"	92 SF 00	
43 RCL 13	93*LBL 00	
44 2	94 XEQ 04	
45 X=Y?	95 XEQ 02	
46 "G-R"	96 RCL 07	
47 "F LTD"	97 PCL 12	
48 AVIEW	98 /	
49 RTN	99 LN	
50*LBL C	100 14388	
	101 /	
	102 RCL 13	
	103 *	

7. HCT, X, EG.



SAMPLE DATA AND RESULTS

CUTOFF	CALCULATION TO FIND X			X	FOR A NEW		USE X TO FIND:	
	BANDGAP	TEMPERATURE			TEMPERATURE	BANDGAP	CUTOFF	
4.2		195		.31879	80	.27342		4.543
	0.3	195		.32173	80	.27806		4.459

- Registers used: 4 — Cutoff wavelength OR bandgap
 5 — Temperature
 6 — "X" alpha label for SV program
 7 — X, either from direct entry or left by SV program
 8 — Used by SV
 9 — Used by SV

This program uses the empirical equation for bandgap in terms of temperature and X value developed by Hansen, Schmidt, and Casselman (HSC)¹, which is valid for a wide range of X:

$$E_g = -.302 + 1.93 X + (5.35E-4)T(1 - 2X) - 0.810 X^2 + 0.832 X^3.$$

It is generally desirable to determine the bandgap or cutoff that a device would have at some temperature from data which are available at some other temperature. The parameter which remains fixed in such calculations is the material composition, X. If X is known, it is stored into the program via label C; labels D and E calculate bandgap or cutoff directly from temperature. Sometimes, however, the data provided does not include X, so the HSC equation is solved iteratively for X as a function of T and (Eg or cutoff) through the use of labels A or B. The value found for X is displayed and saved by the program for use by D and E.

This program solves the HSC equation for X by calling the SV program, described elsewhere (par 5.), and searching for a root of the equation $HSC - E_g = 0$.

Global labels available from this program are HCT which behaves like local label A and may be used to find X from cutoff and temperature, and EG which calculates Eg from an internally stored value for T and an X in the X register. Of course, these may be called from other programs.

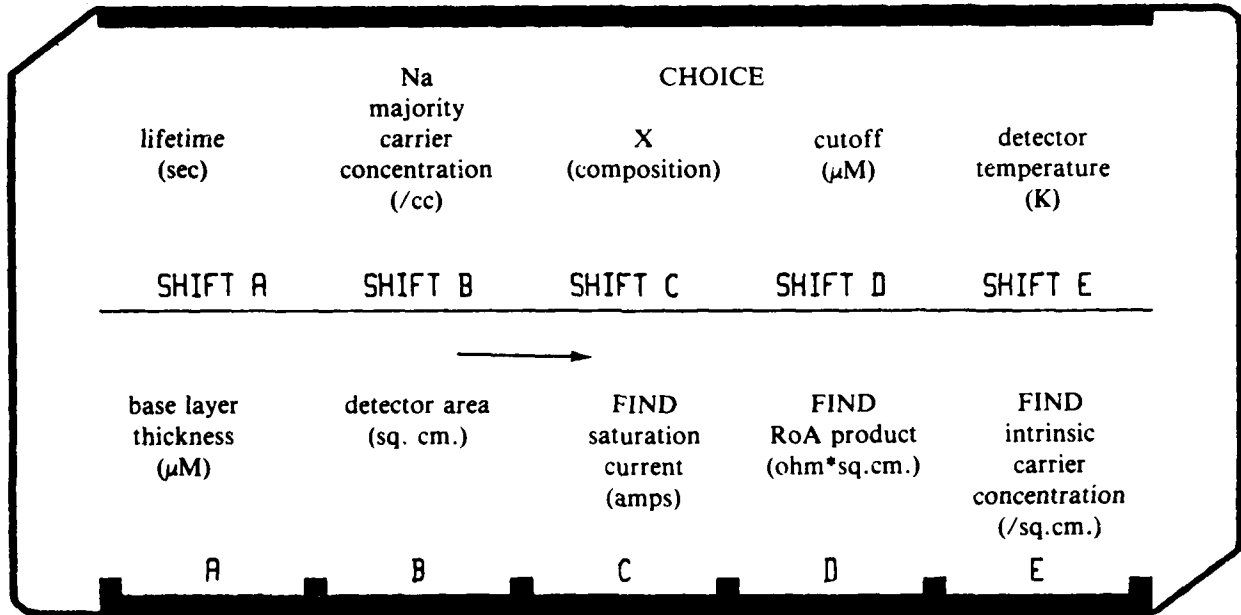
¹Hansen, Schmidt, and Casselman (HSC), J. Appl. Phys. 53, 7099; 1982.

PROGRAM LISTING FOR HCT, X, EG

08 AUG 86

01*LBL "HCT"	34 RTN
02*LBL A	35*LBL D
03 CF 00	36 STO 05
04 GTO 01	37 RCL 07
05*LBL B	38*LBL 00
06 SF 00	39*LBL "EG"
07*LBL 01	40 ENTER↑
08 FIX 9	41 ENTER↑
09 "X"	42 ENTER↑
10 ASTO 06	43 .832
11 STO 05	44 *
12 RDN	45 .81
13 STO 04	46 -
14 CLX	47 *
15 ENTER↑	48 1.93
16 .25	49 +
17 SF 10	50 5.35 E-4
18 XEQ "SV"	51 RCL 05
19 RTN	52 *
20*LBL E	53 ENTER↑
21 XEQ D	54 RDN
22 1.242	55 ST+ X
23 /	56 -
24 1/X	57 *
25 RTN	58 +
26*LBL "X"	59 .302
27 XEQ 00	60 -
28 FC? 00	61 RTN
29 1.242	62*LBL C
30 RCL 04	63 STO 07
31 FC? 00	64 END
32 /	
33 -	

8. NI, RoA.



Below is a table showing the data required, registers used, sample data, and results.

	TEST DATA	REGISTER USED
MINORITY CARRIER LIFETIME (s)	1E-7	1
MAJORITY CARRIER CONCENTRATION (/cm ³)	5E15	2
COMPOSITION (X) OR	.21200	7
CUTOFF WAVELENGTH (μM)	12	4
DETECTOR TEMPERATURE (K)	80	5
BASE LAYER THICKNESS (μM)	10	3
DETECTOR AREA (cm ²) (only req'd for Isat)	6.45E-6	12
RESULTS FOR CUTOFF = 12		
INTRINSIC CARRIER CONCENTRATION (/cm ³)	3.551E13	
PREDICTED RoA (ohm*cm ²)	17.064	
SATURATION CURRENT (A)	2.606E-9	

This program uses the following equation to solve for RoA. It assumes that the device is diffusion limited, that the diffusion length is much longer than the base layer is thick, and that surface effects are not present. Also, lateral collection effects are not considered, unless one takes the A as the effective carrier collecting area and not the junction area.

$$RoA = \frac{k T N_a t}{e^2 d N_i^2}$$

- where e is the charge on an electron;
- t is the minority carrier lifetime;
- k is Boltzmann's constant;
- T is the detector temperature;
- d is the base layer thickness;
- N_a is the majority carrier concentration; and
- N_i is the intrinsic carrier concentration.

All these parameters are user input, except the intrinsic carrier concentration which must be solved for from the detector temperature (already input), and the material composition (X). The equation used is from Hansen and Schmidt²:

$$N_i = [5.585 - 3.820 X + (1.753E-3)T - (1.364E-3)XT] [(10^{14})E_g^{-0.75}T^{1.5}e^{-E_g/2kT}].$$

You have the option of providing the material cutoff wavelength instead of X, in which case, the program calls the HCT program to solve for X, and uses (1.24/cutoff) for Eg. If X is provided instead of the cutoff, the program calls the EG program to find Eg. NI keeps track of whether X or the cutoff has been input (and selected to predominate.) For example, if calculations are done for various device temperatures and X predominates, new values for Eg will be calculated at each temperature. If cutoff predominates, new values of X will be calculated at each temperature. If it is desired that the X value predominate, but only the cutoff is known, run the program once entering the known cutoff. Then, EITHER quickly jot down the X value that is briefly displayed and key it in via SHIFT C prior to any further calculations, OR merely clear flag 2.

The diode diffusion limited saturation current may be found, once the RoA is known, IF the diode area is known. The equation used is:

$$I_{sat} = \frac{k T}{e R_o}, \text{ where } R_o = \frac{R_o A}{A}$$

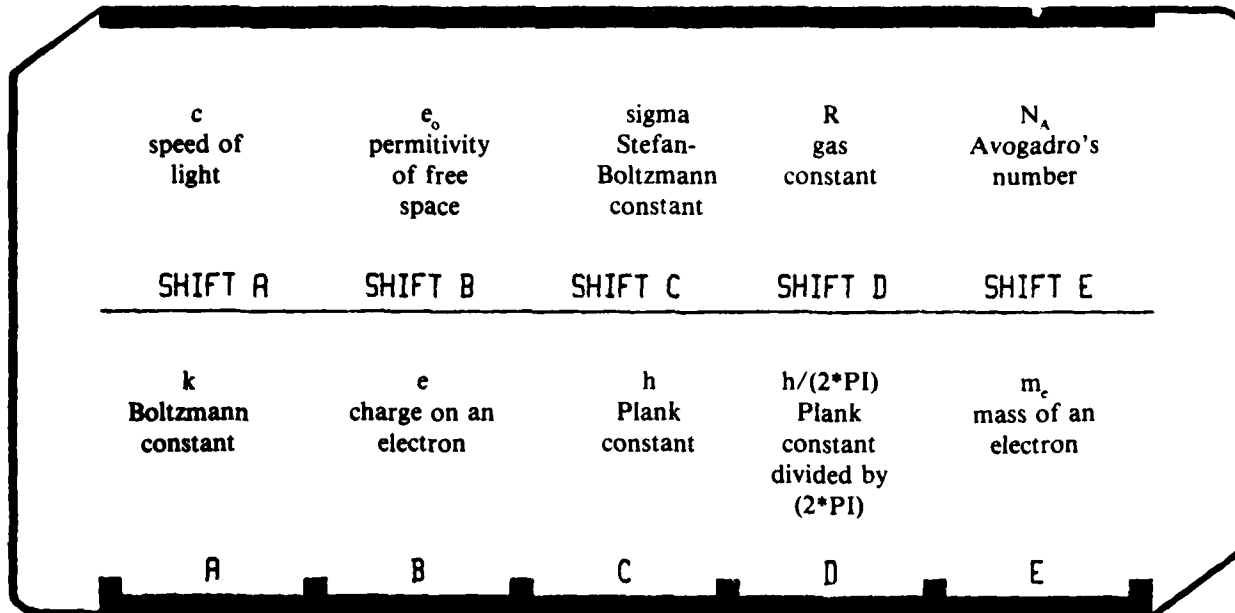
As a point of interest, viewing the program code for LBL C (Isat), one observes that, despite the fact that R0A should be executed as a subroutine, the R0A routine is not run via an XEQ (which is a subroutine call) but via a GTO (which is a jump); and that R0A returns to the Isat routine based on the status of flag 3. The reason for this more-involved method for calling R0A lies in the fact that the HP41's RTN (return) stack is, only, six levels deep. This stack is where the HP41 keeps track of the location from which a subroutine has been called (the location where it must return at the end of a subroutine.) Following the program code, one finds that R0A calls NI, which may call label 01, which calls HCT, which calls SV, which calls X, which calls EG. If one tries to use R0A as a subroutine, the return address in the initial calling program gets pushed off the stack (and lost), when EG gets called; so the program terminates (incorrectly) in R0A.

²Hansen and Schmidt, J. Appl. Phys. 54, 3; March 1983.

PROGRAM LISTING FOR NI, R0A

01/10/1986	51*LBL 02	103*LBL a
01*LBL "NI"	52 RCL 07	104 STO 01
02*LBL E	53 XEQ "EG"	105 RTN
03 RCL 11	54 1.24	106*LBL b
04 FS? 01	55 /	107 STO 02
05 RTN	56 1/X	108 RTN
06 FS? 02	57 FIX 2	109*LBL c
07 XEQ 01	58 "a="	110 STO 07
08 FC? 02	59 ARCL X	111 CF 01
09 XEQ 02	60 AVIEW	112 CF 02
10 -1.364	61 STO 04	113 RTN
11 RCL 05	62 RCL 07	114*LBL d
12 *	63 RTN	115 STO 04
13 3820	64*LBL "R0A"	116 CF 01
14 -	65*LBL D	117 SF 02
15 *	66 FIX 3	118 RTN
16 1.753	67 XEQ E	119*LBL e
17 RCL 05	68 5378 E15	120 STO 05
18 *	69 X<Y	121 CF 01
19 +	70 X^2	122 RTN
20 5585	71 /	123*LBL A
21 +	72 RCL 05	124 STO 03
22 E11	73 *	125 END
23 *	74 RCL 02	
24 1.24	75 *	
25 RCL 04	76 RCL 03	
26 /	77 /	
27 SQRT	78 RCL 01	
28 RCL 05	79 *	
29 *	80 "RA="	
30 SQRT	81 ARCL X	
31 3	82 AVIEW	
32 Y^X	83 FS?C 03	
33 *	84 GTO 03	
34 7194	85 RTN	
35 RCL 04	86*LBL B	
36 /	87 STO 12	
37 RCL 05	88 RTN	
38 /	89*LBL C	
39 E^X	90 SF 03	
40 /	91 GTO D	
41 SF 01	92*LBL 03	
42 STO 11	93 RCL 12	
43 CLB	94 /	
44 FIX 3	95 RCL 05	
45 RTN	96 /	
46*LBL 01	97 11605	
47 RCL 04	98 *	
48 RCL 05	99 1/X	
49 XEQ "NCT"	100 "I="	
50 RTN	101 ARCL X	
	102 PROMPT	

9. CONSTNT.



This program may be used to conveniently bring any of the available physical constants into the X register for use in direct keyboard calculations. All constants are in MKS units. When any of the keys are pressed (SHIFT A through SHIFT E, or A through E) the current value in the X register is pushed up into the Y register, and the selected constant is placed in the X register. For example, suppose one wants to evaluate the following expression:

$$\frac{h c}{\text{wavelength } k T}$$

where wavelength = 4.2E-6 m,
and T = 300 K.

The sequence that may be followed is:

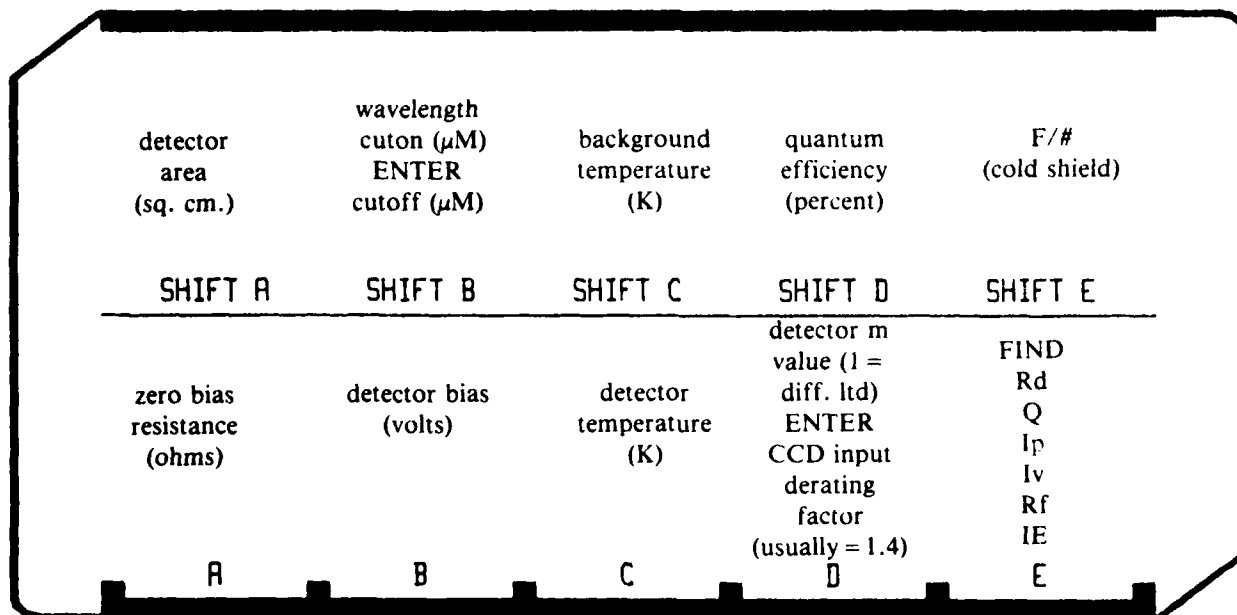
PRESS	TO OBTAIN	SEE
SHIFT SCI 4	Floating point display and 5 significant figures	
C	h	6.6262 -34
SHIFT A	c	2.9979 08
*	Multiply X and Y registers	1.9865 -25
4.2 EEX CHS 6	Wavelength	4.2 -6
/	Divide Y register by X	4.7297 -20
A	k	1.3806 -23
/	Divide Y register by X	3.4258 03
300	T	300
/	Divide Y register by X	1.1419 01

PROGRAM LISTING FOR CONSTNT

01/10/1986

01*LBL *CONSTNT*
02*LBL a
03 2.997925 E8
04 RTN
05*LBL A
06 1.38062 E-23
07 RTN
08*LBL B
09 1.6022 E-19
10 RTN
11*LBL C
12 6.6262 E-34
13 RTN
14*LBL D
15 1.0546 E-34
16 RTN
17*LBL E
18 9.1096 E-31
19 RTN
20*LBL e
21 6.02217 E23
22 RTN
23*LBL b
24 8.85 E-12
25 RTN
26*LBL c
27 5.66961 E-8
28 RTN
29*LBL d
30 8.31434
31 RTN
32 END

10. INJEFF.



Below is a table showing the data required, registers used, sample data, and results:

PARAMETER	REGISTER USED	SAMPLE DATA	RESULTS
DETECTOR AREA, A	16	1E-5	
CUTON	5	3.0	
CUTOFF	10	5.0	
BACKGROUND TEMPERATURE	12	300	
QUANTUM EFFICIENCY	17	80	
COLD SHIELD F/#	13	1	
ZERO BIAS RESISTANCE, Ro	9	1E6	
DETECTOR BIAS, V	2	- .02	
DETECTOR TEMPERATURE	14	200	
DETECTOR m VALUE (1 = DIFF. LTD., 2 = G-R LTD.)	3	1.2	
CCD DERATING FACTOR (m FOR CCD INPUT NODE)	11	1.4	

Rd = DIODE DYNAMIC RESISTANCE (OHMS)	1		2.63E6
Q = PHOTON FLUX (/cm ² /s)	15		1.31E16
Ip = DIODE PHOTOCURRENT (A)			4.20E-9
Iv = DIODE BIAS CURRENT (A)			1.28E-8
Rf = CCD INPUT IMPEDANCE (OHMS) (RECIPROCAL OF TRANSCONDUCTANCE)			1.42E6
IE = INJECTION EFFICIENCY			0.650

Other registers used: 4, 6, 7, 8

This program calculates injection efficiency from the equation:

$$IE = \frac{R_d}{(\text{CCD derating factor})R_f + R_d}.$$

R_f is the CCD input impedance and is the reciprocal of the term normally used: CCD input transconductance. R_f is computed from:

$$R_f = \frac{k T}{e I_d}, \quad \text{where } I_d \text{ is the net diode current} = I_v + I_p.$$

I_p is the photocurrent induced in the photodiode by the background photon flux, Q , and is:

$$I_p = e A Q (\text{quantum efficiency}).$$

I_v is the diode current due to the fact that a bias is applied and is found from the equation of a diode:

$$I_v = \frac{mkT [\text{EXP}(-eV/\{mkT\}) - 1]}{e R_o}.$$

Finally, R_d is the dynamic resistance of the diode at the specified bias. This may be found by differentiating the equation for I_v with respect to V and taking the reciprocal, so that:

$$R_d = R_o \text{EXP}(-eV/\{mkT\}).$$

When E is pressed to compute an injection efficiency, the intermediate results (R_d , Q , I_p , I_v , R_f), with identification, are flashed in the display, as they are found. The program stops with the injection efficiency displayed. If a printer is connected to the HP 41 and is on before the HP41 is turned on, all results will be printed. These data flash past too fast to be recorded without a printer and, if you're not interested in it, just ignore it. If you ARE interested in the intermediate results, set flag 21 using SHIFT SF 21 prior to pressing E. The HP 41 will stop at each intermediate value so that it may be recorded. Pressing R/S at each of these points will continue the program to the next result, ultimately displaying the value for the injection efficiency. You need set flag 21 only once, and it will remain set until you clear it using the FLAG routine, using SHIFT CF 21, or by turning the HP41 on with no printer connected.

PROGRAM LISTING FOR INJEFF

01/10/1986		
	01*LBL "INJEFF"	51 *Rd="
	02*LBL a	52 ARCL X
	03 STO 16	53 AVIEW
	04 RTN	54 FS? 00
	05*LBL b	55 GTO 00
	06 STO 10	56 CF 02
	07 X<Y	57 RCL 10
	08 STO 05	58 XEQ "QBB"
	09 CF 00	59 STO 15
	10 RTN	60 RCL 05
	11*LBL c	61 XEQ "QBB"
	12 STO 12	62 ST- 15
	13 CF 00	63 SF 00
	14 RTN	64*LBL 00
	15*LBL d	65 RCL 15
	16 STO 17	66 "Q="
	17 RTN	67 ARCL X
	18*LBL e	68 AVIEW
	19 STO 13	69 RCL 17
	20 RTN	70 *
	21*LBL A	71 RCL 13
	22 STO 09	72 X↑2
	23 RTN	73 /
	24*LBL B	74 4 E-22
	25 STO 02	75 *
	26 RTN	76 RCL 16
	27*LBL C	77 *
	28 STO 14	78 CHS
	29 RTN	79 *IP="
	30*LBL D	80 ARCL X
	31 STO 11	81 AVIEW
	32 X<Y	82 RCL 04
	33 STO 03	83 1
	34 RTN	84 -
	35*LBL E	85 RCL 06
	36 SCI 2	86 /
	37 11605	87 RCL 09
	38 RCL 14	88 /
	39 /	89 RCL 03
	40 STO 06	90 *
	41 RCL 02	91 *IV="
	42 *	92 ARCL X
	43 RCL 03	93 AVIEW
	44 /	94 +
	45 E↑X	95 ABS
	46 STO 94	96 RCL 06
	47 1/X	97 *
	48 RCL 09	98 1/X
	49 *	99 RCL 11
	50 STO 01	100 *
		101 *RF="
		102 ARCL X
		103 AVIEW
		104 RCL 01
		105 +
		106 RCL 01
		107 /
		108 1/X
		109 *IE="
		110 FIX 3
		111 ARCL X
		112 AVIEW
		113 END

III. FINAL COMMENTS

As with any software, the results are only as valid as the data, the equations, and the program steps which are intended to represent them. The various programs have been tested and are believed to be correct and functional. However, if any errors are found, if any problems arise, or if you have any comments or questions, please let the author of this report know.

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